

Notice of References Cited	Application/Control No. 10/671,799		Applicant(s)/Patent Under Reexamination HWANG, TIEN-WAN	
	Examiner Shawn M. Braden		Art Unit 3727	Page 1 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,713,461 A	02-1998	Su, Feng-Pai	206/303
*	B	US-5,839,575 A	11-1998	Blanco, Allen R.	206/232
*	C	US-6,123,190 A	09-2000	Kuboduka, Masaaki	206/308.3
*	D	US-6,161,690 A	12-2000	Isozaki, Makoto	206/308.1
*	E	US-6,230,885 B1	05-2001	Rochelo et al.	206/308.3
*	F	US-6,260,725 B1	07-2001	Gonzales et al.	220/4.21
*	G	US-6,343,707 B1	02-2002	Cheng, Tsung-Kan	220/4.24
*	H	US-6,386,382 B1	05-2002	McCausland, William Thomas	220/4.21
*	I	US-6,444,904 B1	09-2002	Holman et al.	174/52.1
*	J	US-6,757,155 B2	06-2004	Koike et al.	361/600
*	K	US-2006/0003609 A1	01-2006	Hwang, Tien-Wan	439/076.1
*	L	US-7,004,343 B2	02-2006	Hiraguchi, Kazuo	220/4.21
*	M	US-2006/0037882 A1	02-2006	Appelbaum et al.	206/471

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

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Notice of References Cited	Application/Control No. 10/671,799	Applicant(s)/Patent Under Reexamination HWANG, TIEN-WAN	
	Examiner Shawn M. Braden	Art Unit 3727	Page 2 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2,631,631 A	03-1953	VOGEL KURT M	206/38.1
*	B	US-4,177,899 A	12-1979	Green et al.	206/509
*	C	US-4,634,004 A	01-1987	Mortensen, Roger L.	206/387.11
*	D	US-5,205,413 A	04-1993	Cautereels et al.	206/541
*	E	US-5,358,134 A	10-1994	Ripley et al.	220/787
*	F	US-5,369,549 A	11-1994	Kopp et al.	361/679
*	G	US-5,398,833 A	03-1995	Klauss et al.	220/4.02
*	H	US-5,427,233 A	06-1995	Zinck et al.	206/69
*	I	US-5,531,345 A	07-1996	Nakamura et al.	220/3.8
*	J	US-5,944,210 A	08-1999	Yetter, Karl	220/4.21
*	K	US-6,041,956 A	03-2000	Kao, Ken	220/4.02
*	L	US-6,060,958 A	05-2000	Tokudera et al.	333/1.1
*	M	US-2001/0032847 A1	10-2001	Cheng, Tsung-Kan	220/4.21

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
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Notice of References Cited	Application/Control No. 10/671,799	Applicant(s)/Patent Under Reexamination HWANG, TIEN-WAN	
	Examiner Shawn M. Braden	Art Unit 3727	Page 3 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,635,809 A	01-1987	Bachman et al.	220/4.21
*	B	US-4,765,501 A	08-1988	Kao, Joe	220/4.21
*	C	US-4,840,286 A	06-1989	Heberling et al.	220/4.02
*	D	US-4,899,257 A	02-1990	Yamamoto, Masato	361/740
*	E	US-5,233,506 A	08-1993	Semenik et al.	361/814
*	F	US-5,258,888 A	11-1993	Korinsky, George K.	361/704
*	G	US-5,383,098 A	01-1995	Ma et al.	361/818
*	H	US-5,526,234 A	06-1996	Vinciarelli et al.	361/740
*	I	US-5,823,641 A	10-1998	Goto et al.	312/7.2
*	J	US-2004/0040871 A1	03-2004	Kakinoki et al.	206/307
*	K	US-2004/0079655 A1	04-2004	Hsieh et al.	206/307
*	L	US-2006/0005587 A1	01-2006	Necchi, Pietro	070/057.1
*	M	US-2006/0060579 A1	03-2006	Guarrascio, Bernard	220/004.21

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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Notice of References Cited	Application/Control No. 10/671,799	Applicant(s)/Patent Under Reexamination HWANG, TIEN-WAN	
	Examiner Shawn M. Braden	Art Unit 3727	Page 4 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,836,408 A	06-1989	Roy, Dhirendra C.	220/4.02
*	B	US-5,669,499 A	09-1997	Chen, Tsong-Hsien	206/387.1
*	C	US-6,443,306 B1	09-2002	Davies et al.	206/473
	D	US-			
	E	US-			
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	N					
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